

Substitute Form PTO-1449
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Patent and Trademark OfficeAttorney's Docket No.
09712-057001Application No.
09/769,859**Information Disclosure Statement
by Applicant**

(Use several sheets if necessary)

(37 CFR §1.98(b))

Applicant
Peter de Groot et al.Filing Date
January 25, 2001

Group Art Unit

U.S. Patent Documents

Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
JFA	AA	5,398,113	03 1995	de Groot			
	AB	5,598,265	01 1997	de Groot			
	AC	5,777,738	07/1998	Kulawiec			

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AD							
	AE							
	AF							
	AG							
	AH							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
JFA	AI	Dresel et al., "Three Dimensional Sensing of Rough Surfaces by Coherence Radar," APPLIED OPTICS, 31 7:919-925, March 1, 1992.
	AJ	Ikonen et al., "Interferometric Calibration of Gauge Blocks by Using One Stabilized Laser and a White-light Source," APPLIED OPTICS, 30:31:4477-4478, November 1, 1991.
	AK	Lewis, "Measurement of Length, Surface Form and Thermal Expansion Coefficient of Length Bars up to 1.5 m Using Multiple-wavelength Phase-stepping Interferometry," MEAS. SCI. TECHNOL. 5 694-703, (1994).
	AL	Malinovsky et al., "Toward Subnanometer Uncertainty in Interferometric Length Measurements of Short Gauge Blocks," APPLIED OPTICS, 38:1:101-112, January 1, 1999.
	AM	Nurge et al., "Measurement of Curvature and Thickness Variations of Flat Cuboids by Grazing Incidence Interferometry," Annual Report, Physikalisches Institut Universitat Erlangen-Nurnberg, Lehrstuhl fur Optik, (Druckerei Lengenfelder, Erlangen, Germany, 1998, Page 30.
	AN	Poole et al., "Application of Interferometry to the Routine Measurement of Block Gauges," OPTICS AND METROLOGY, Pol Mollet, Ed., Pergamon Press, New York, 1960.
	AO	Pugh et al., "Automatic Gauge Block Measurement Using Multiple Wavelength Interferometry," SPIE, 656:244-250, 1986.
	AP	Denes et al., "Flatness, Parallelism and Oxyther Novel Uses of Grazing-Incidence Interferometry in Precision Engineering," PROCEEDINGS OF THE ASPE, 11:20-23 (1995).

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Substitute Disclosure Form (PTO-1449)